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APPLICANTS Ryuji Kohno, Chiyoda, JAPAN; Hideo Miura, Koshigaya, JAPAN; Masatoshi Kanamaru, Miho, JAPAN; Hiroya Shimizu, Ryuugasaki, JAPAN; Naoto Ban, Sagamihara, JAPAN;				
** CONTINUING DATA ***** None <i>21</i>				
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IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 09/13/2001				
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input checked="" type="checkbox"/> Met after Allowed and Acknowledged <i>21</i> Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 11
INDEPENDENT CLAIMS 12				
ADDRESS 020457				
TITLE Semiconductor device testing apparatus and semiconductor device manufacturing method using it				
FILING FEE RECEIVED 1560	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit	

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